# Auger Electron Spectroscopy (AES)

innovations
for high
performance
microelectronics

## Technical Parameters

**Auger Electron Spectrometer**:
Physical Electronics PHI 670 Nanoprobe

**Ion source**: $Ar^+$ Ions (Energy 1-5 keV)

**Primary Beam:** focused electron beam (1 - 25 keV) – Field emitter
**Signal Detected:** Auger electrons, Secondary electrons

**Elements Detected:** Li-U; Chemical bonding information

**Lateral Resolution:** 100 nm
**Depth Resolution:** 2 – 3 nm (Profiling mode)
**Detection Limits:** 0.1-1at% sub-monolayer

## Application areas

- Surface analysis
- Particle analysis
- Small-area depth profiling
- Defect analysis
- Thin film composition analysis

## Contact person


Dr. Ioan Costina

Phone: +49 335 5625 370

Fax: +49 335 5625 327

Email: costina@ihp-microelectronics.com